

**Notice of References Cited**

Application/Control No.

09/755,740

Applicant(s)/Patent Under  
Reexamination  
LORD ET AL.

Examiner

Le Nguyen

Art Unit

2174

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,028,602	02-2000	Weidenfeller et al.	345/781
	B	US-6,448,985	09-2002	McNally, Michael R.	345/784
	C	US-6,252,597	06-2001	Lokuge, Ishantha	345/841
	D	US-6,466,239	10-2002	Ishikawa, Masayuki	345/850
	E	US-6,078,327	06-2000	Liman et al.	345/854
	F	US-5,917,492	06-1999	Bereiter et al.	345/854
	G	US-5,923,328	07-1999	Griesmer, James P.	345/854
	H	US-6,559,871	05-2003	Brozowski et al.	345/853
	I	US-5,977,971	11-1999	Guzak et al.	345/853
	J	US-6,380,957	04-2002	Banning, Kenneth Ray	345/828
	K	US-6,237,006	05-2001	Weinberg et al.	256/31
	L	US-5,701,137	12-1997	Kiernan et al.	345/853
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.